

The role of native defects and their diffusivity in CdTe

[Intuon Chatratin](#), Igor Evangelista, and Anderson Janotti

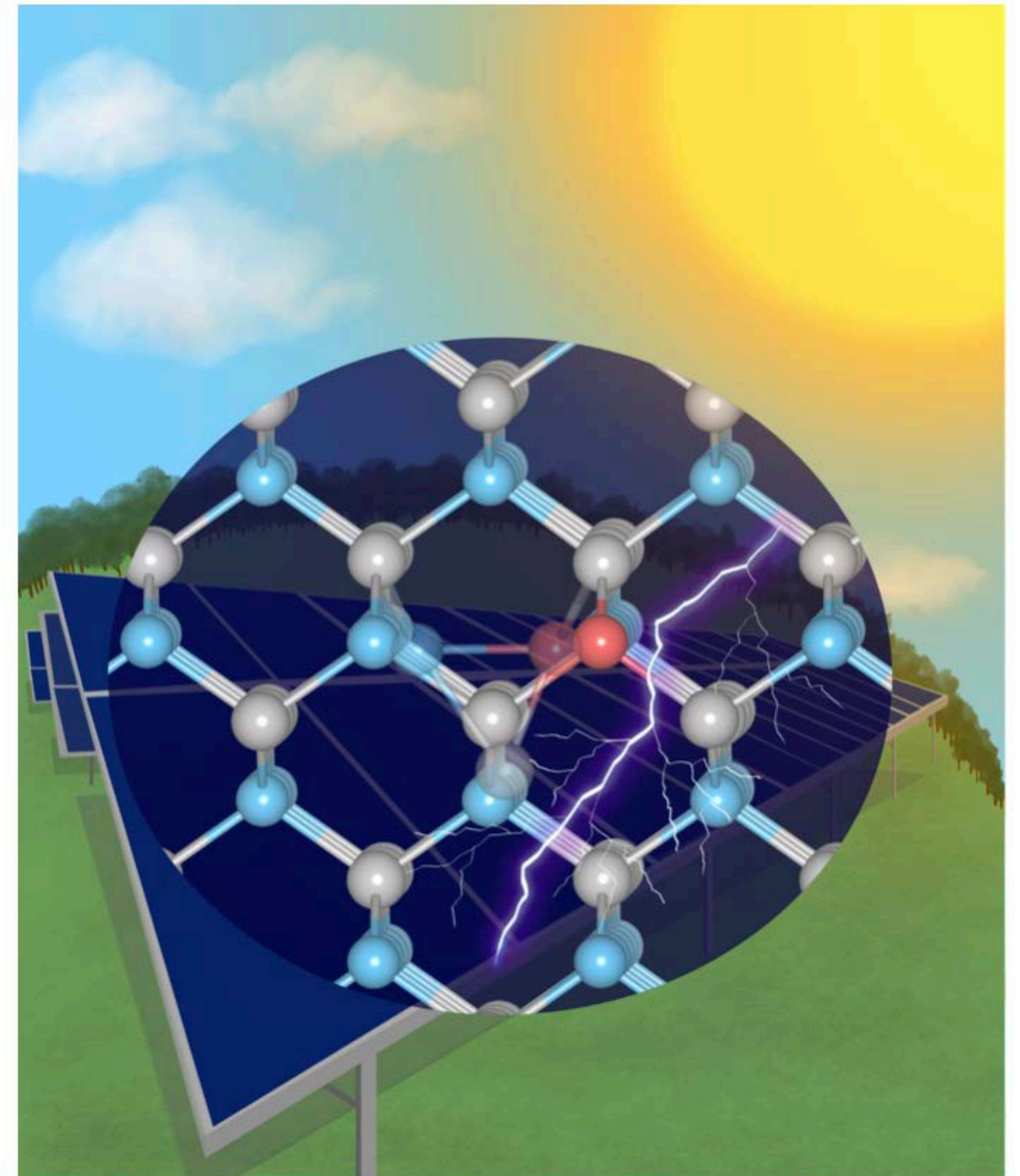
Department of Materials Science and Engineering

University of Delaware



**SOLAR ENERGY
TECHNOLOGIES OFFICE**
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CdTe solar cells

○ Most competitive PV thin-film technology

- low production cost
- simple manufacturing
- record efficiency is 19 % for modules (First Solar)

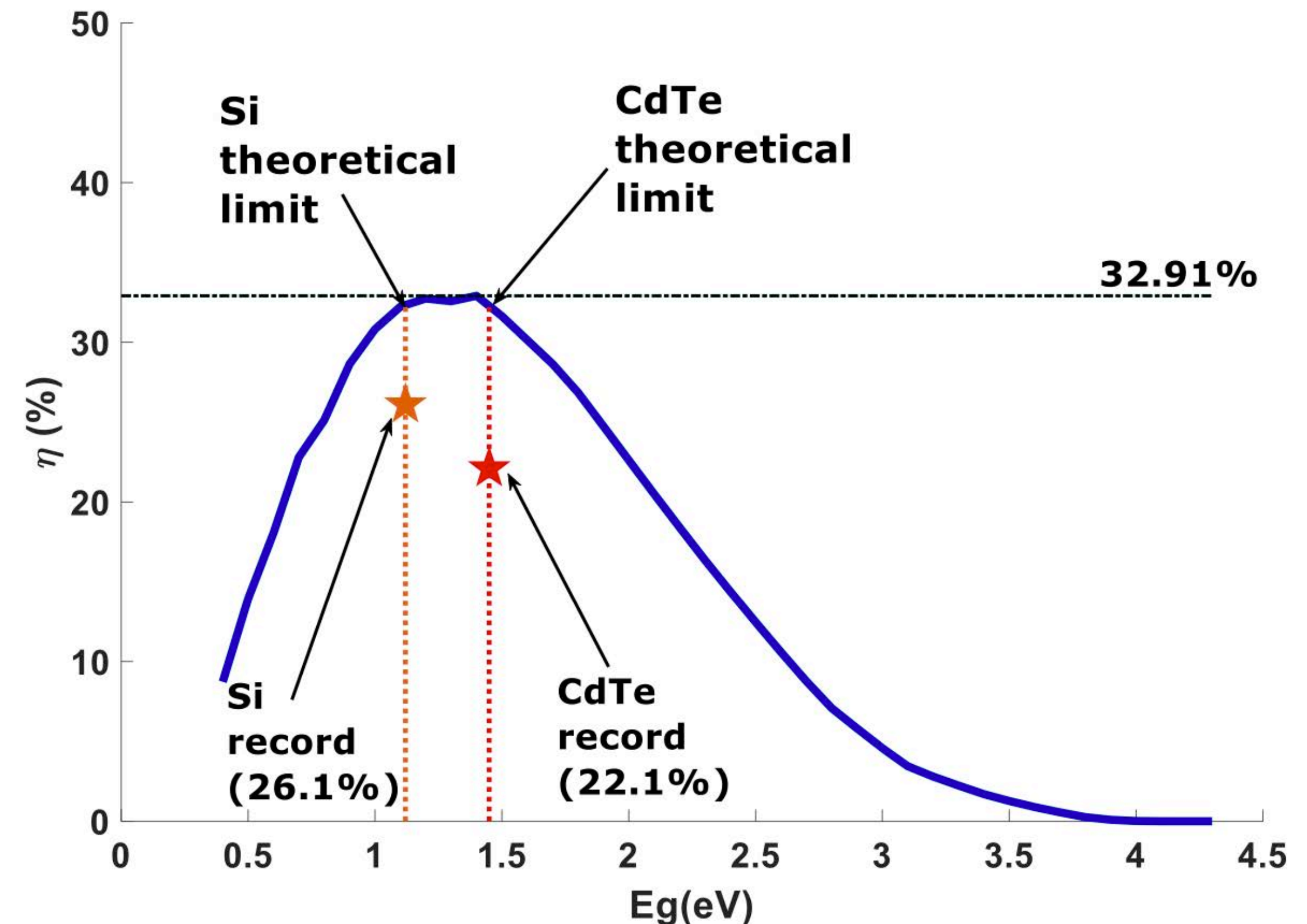
Barbato *et. al.* J. Phys. D Appl. Phys. **54**, 333002 (2021)

First Solar Series 7, <https://www.firstsolar.com/en/Modules/Series-7>

○ Current record in lab > 22%

- low Voc ($\ll E_g$)
- short carrier lifetime
- low hole concentration ($\sim 10^{14} \text{ cm}^{-3}$)
- defects in **bulk** and at interface/surface

M. Green *et al.*, Solar Cell Efficiency Tables, Progress in Photovoltaics: Research and Applications **29**, 3 (2021)



Doping and defects in CdTe

- Group-V impurities (As, P and Sb) are shallow acceptors in CdTe

B. E. McCandless *et al.*, Sci. Rep. **8**, 14519 (2018)

W. K. Metzger *et al.*, Nat. Energy **4**, 837 (2019)

A. Nagaoka *et al.*, Appl. Phys. Lett. **116**, 132102 (2020)

I. Chatratin *et al.*, J. Phys. Chem. Lett. **14**, 273 (2023)

- Observed doping efficiencies are quite low;
source of hole compensation is unknown

Which defects act as hole killers?

Formation energies and stability

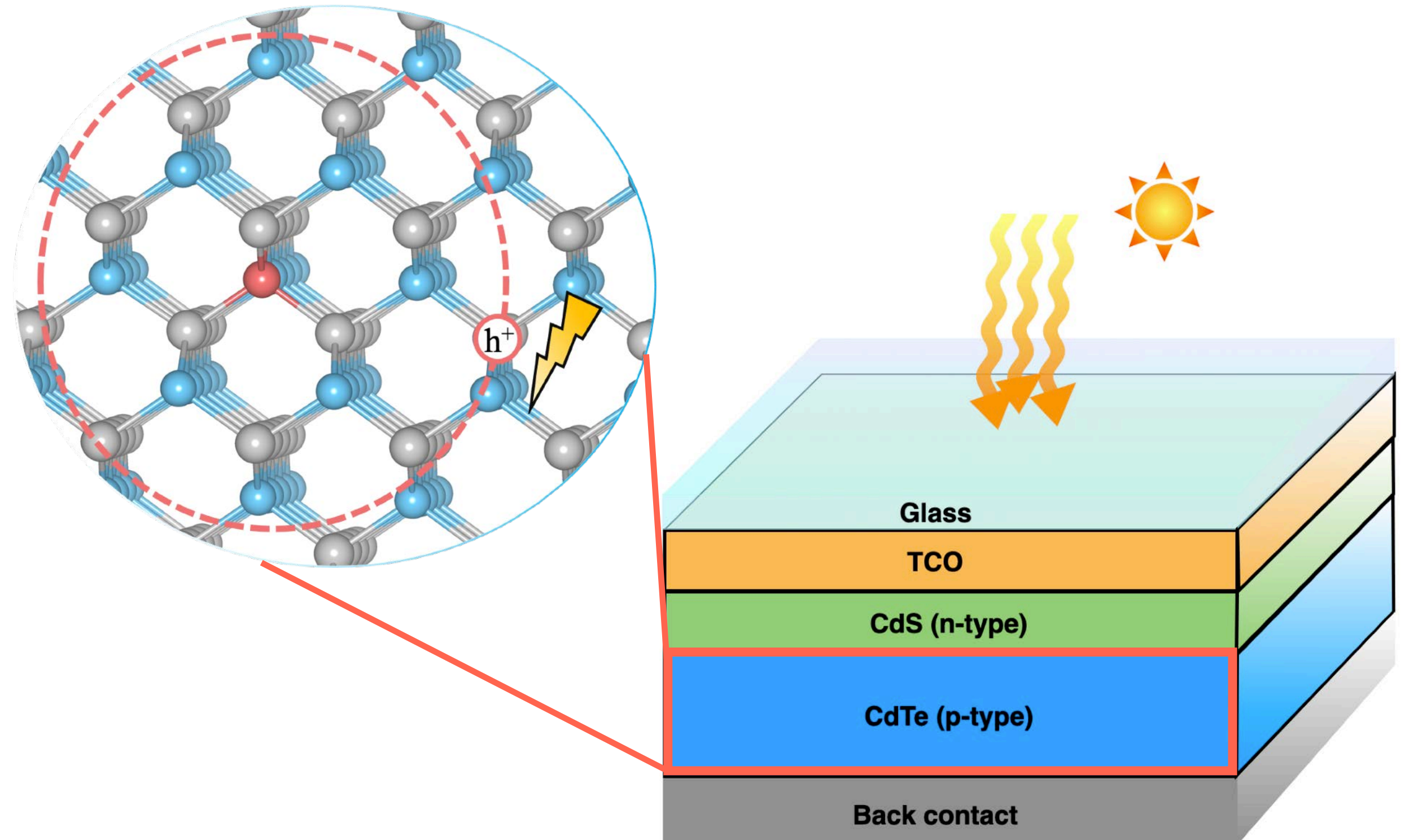
S.-H. Wei and S. B. Zhang, Phys Rev B **66**, 155211 (2002)

M.-H. Du *et al.*, J Appl Phys **104**, 93521 (2008)

J.-H. Yang *et al.*, Semicond Sci Technol **31**, 083002 (2016)

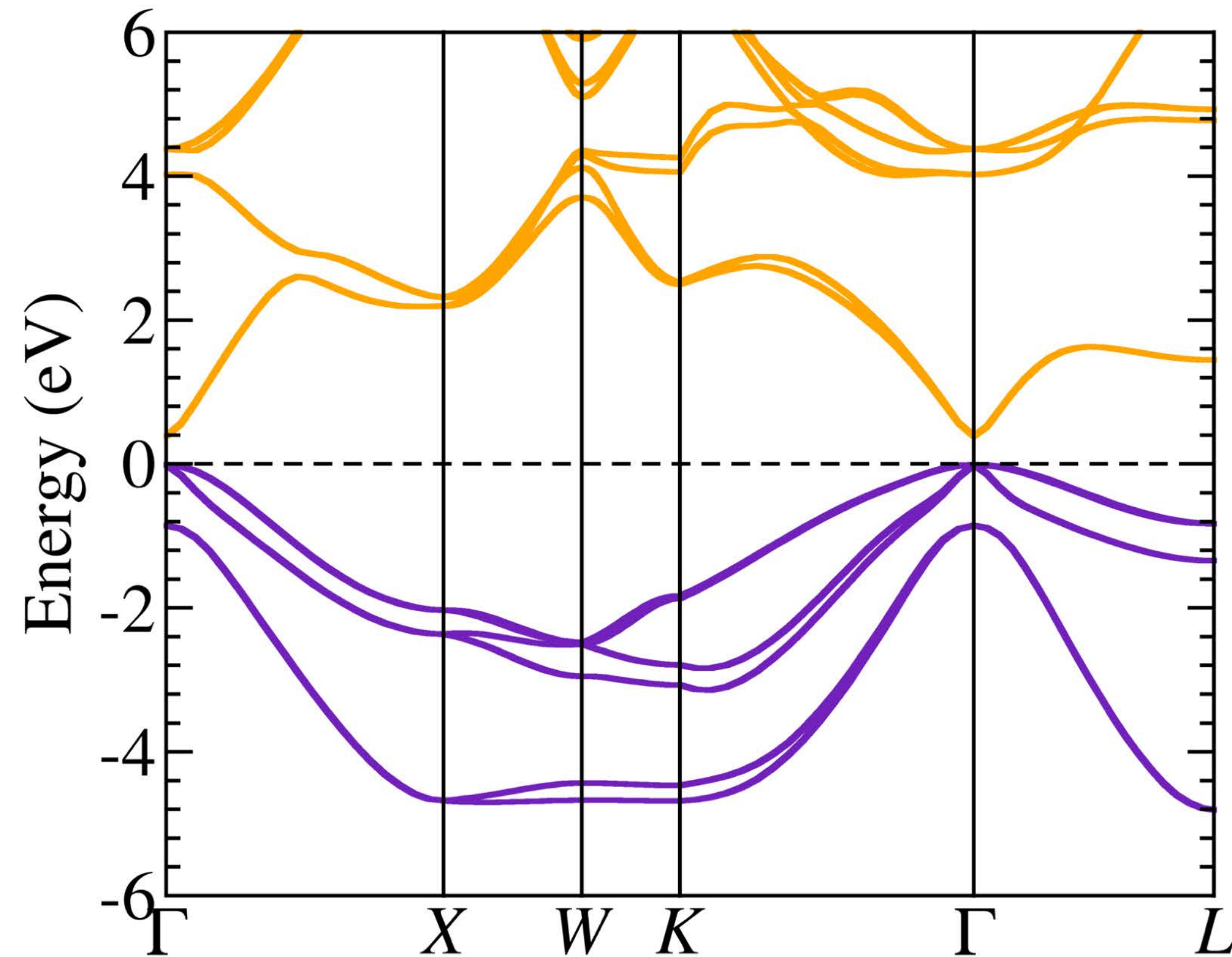
J. Pan *et al.*, Phys Rev B **98**, 054108 (2018)

S. R. Kavanagh *et al.*, ACS Energy Lett **6**, 1392 (2021)



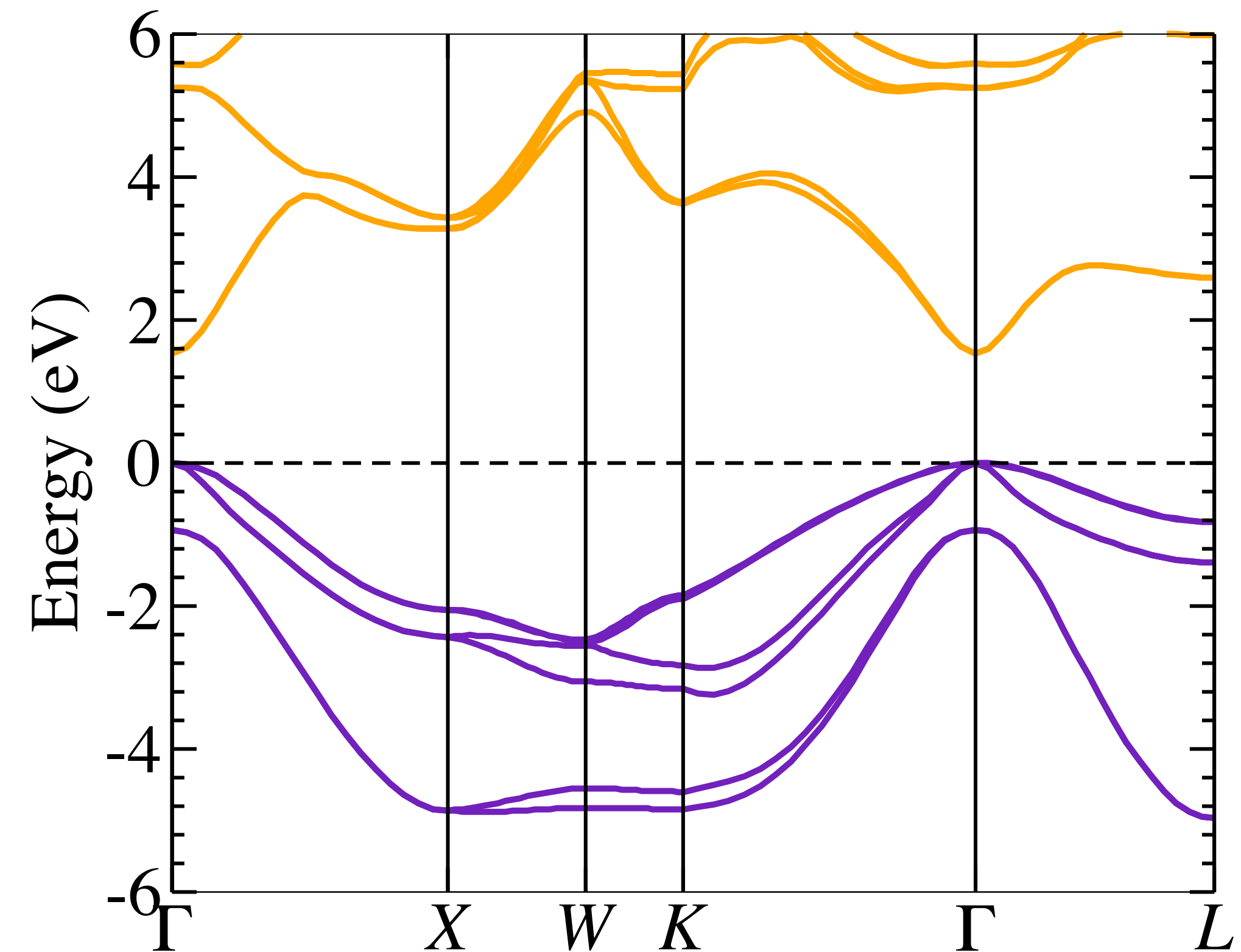
Electronic structure of CdTe

DFT-GGA + SOC



Band gap drastically underestimated

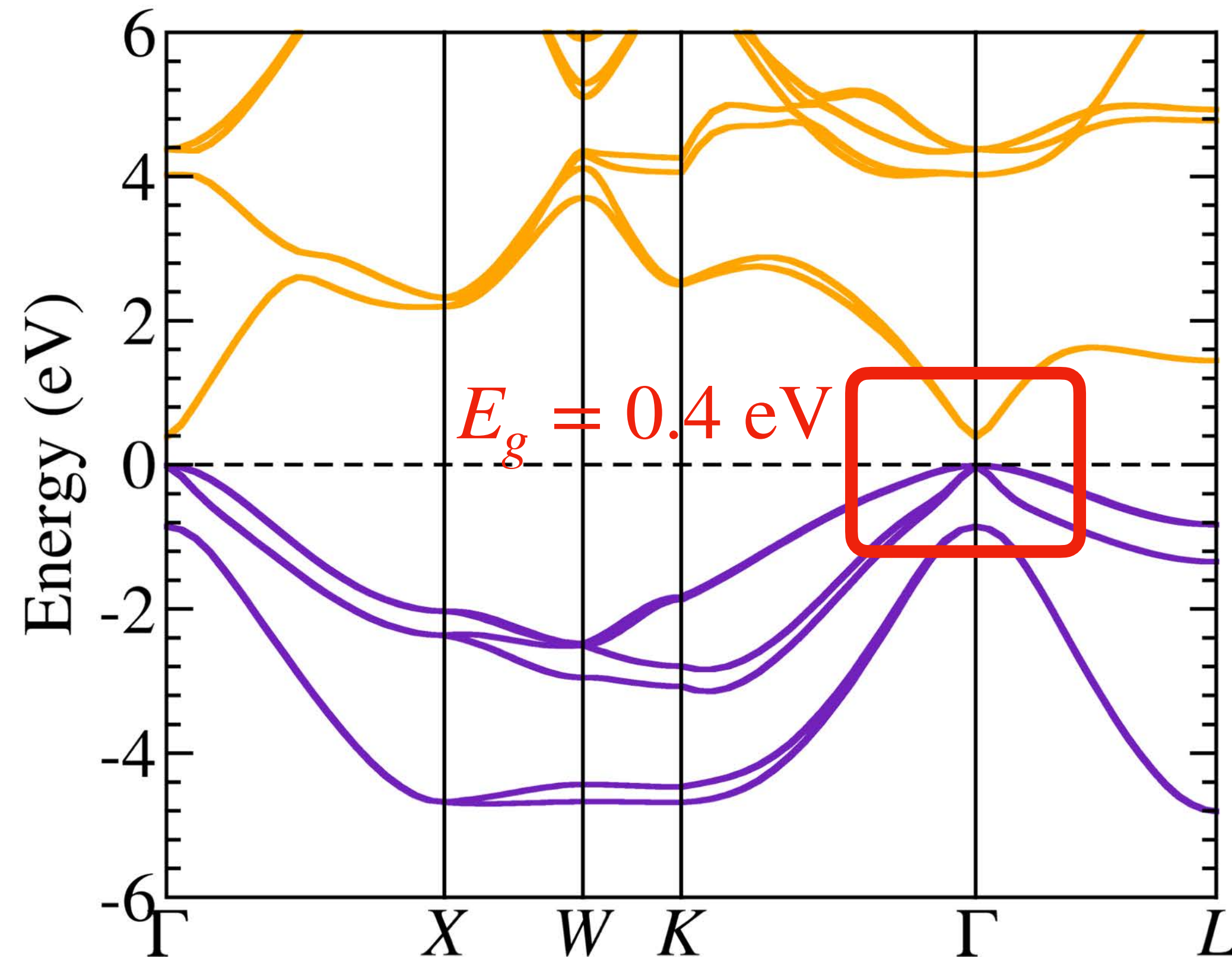
**Hybrid DFT + SOC
(Hartree Fock mixing of 33%)**



**Correct band gap, effective masses,
and ionization potential**

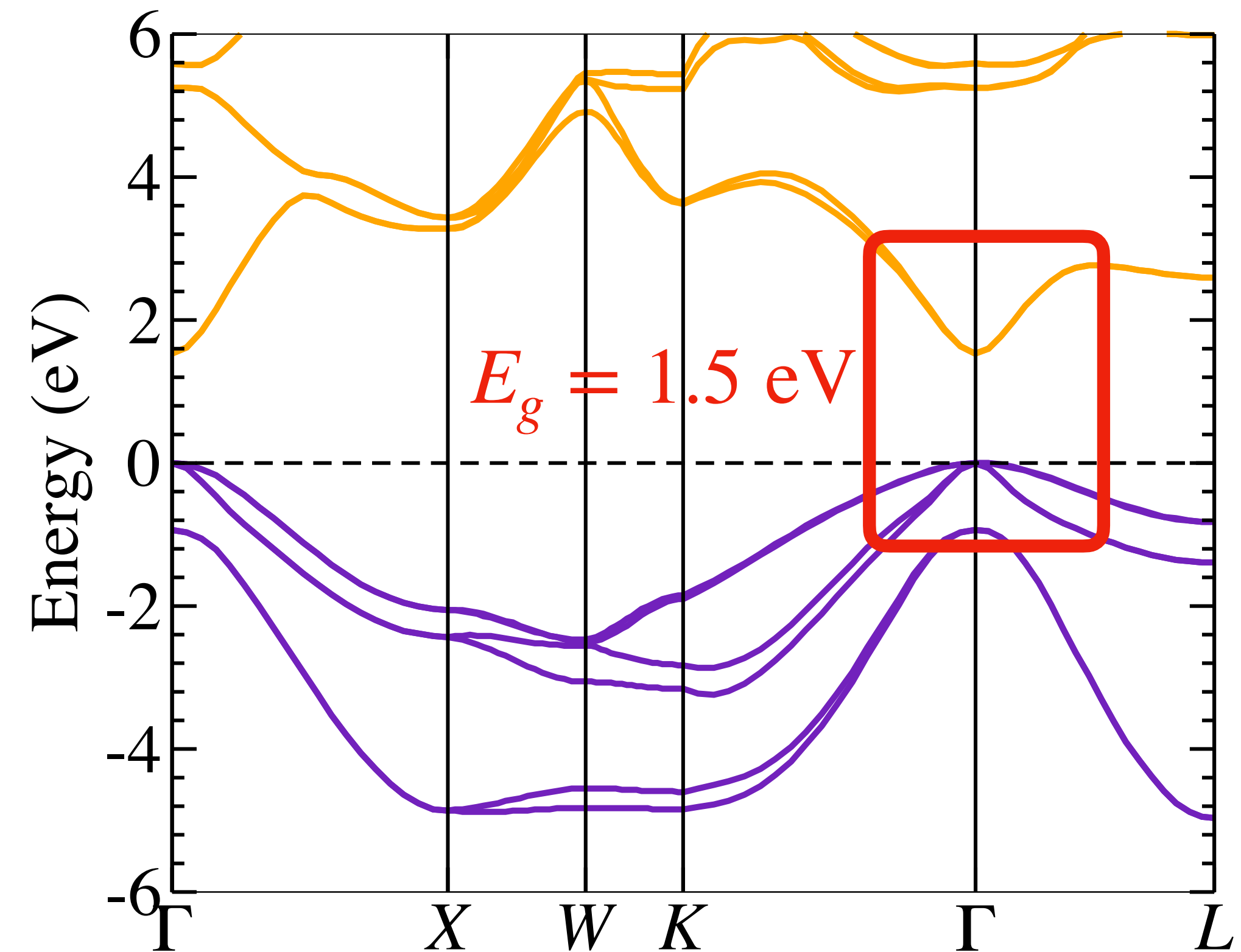
Electronic structure of CdTe

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Band gap drastically underestimated

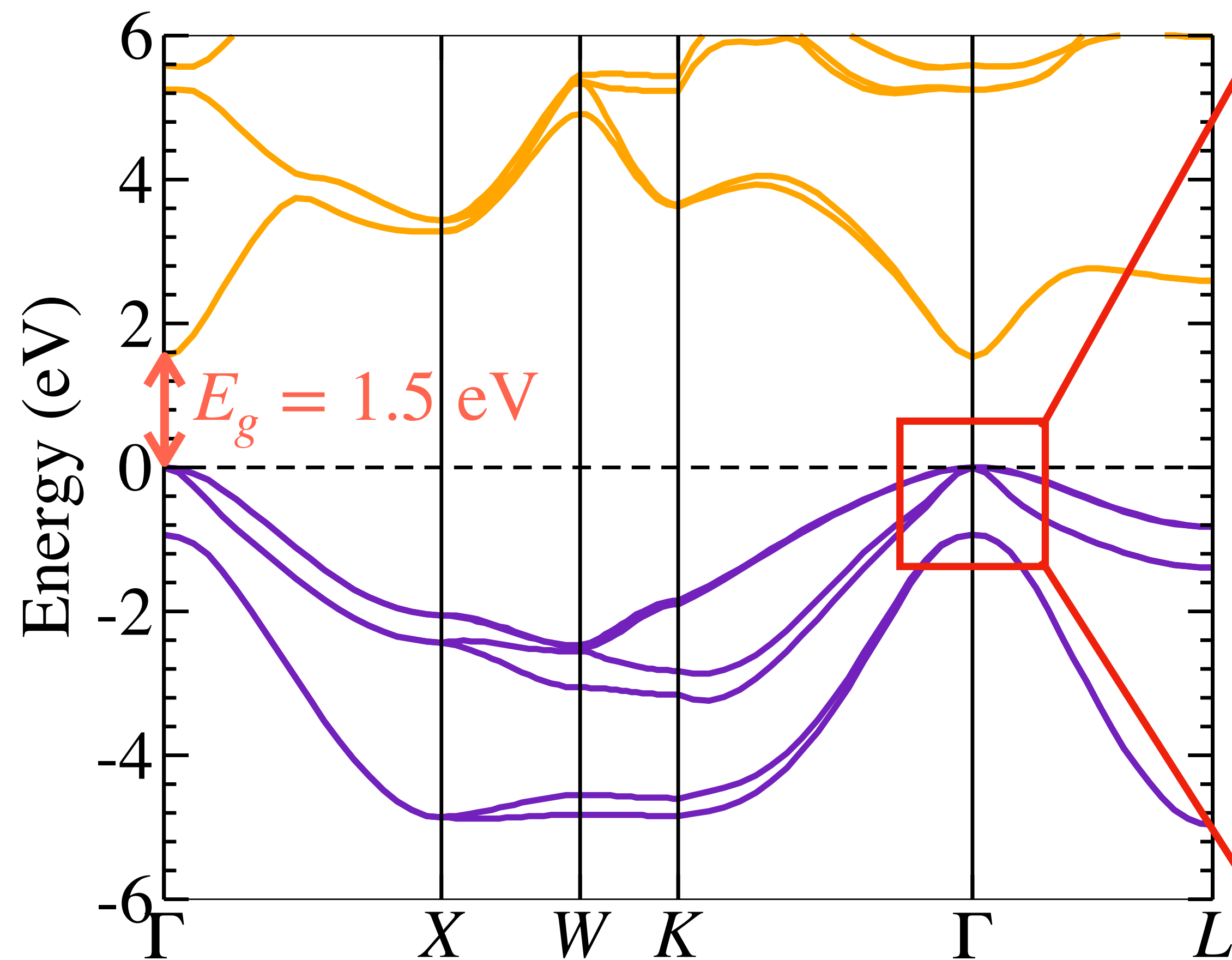
**Hybrid DFT + SOC
(Hartree Fock mixing of 33%)**



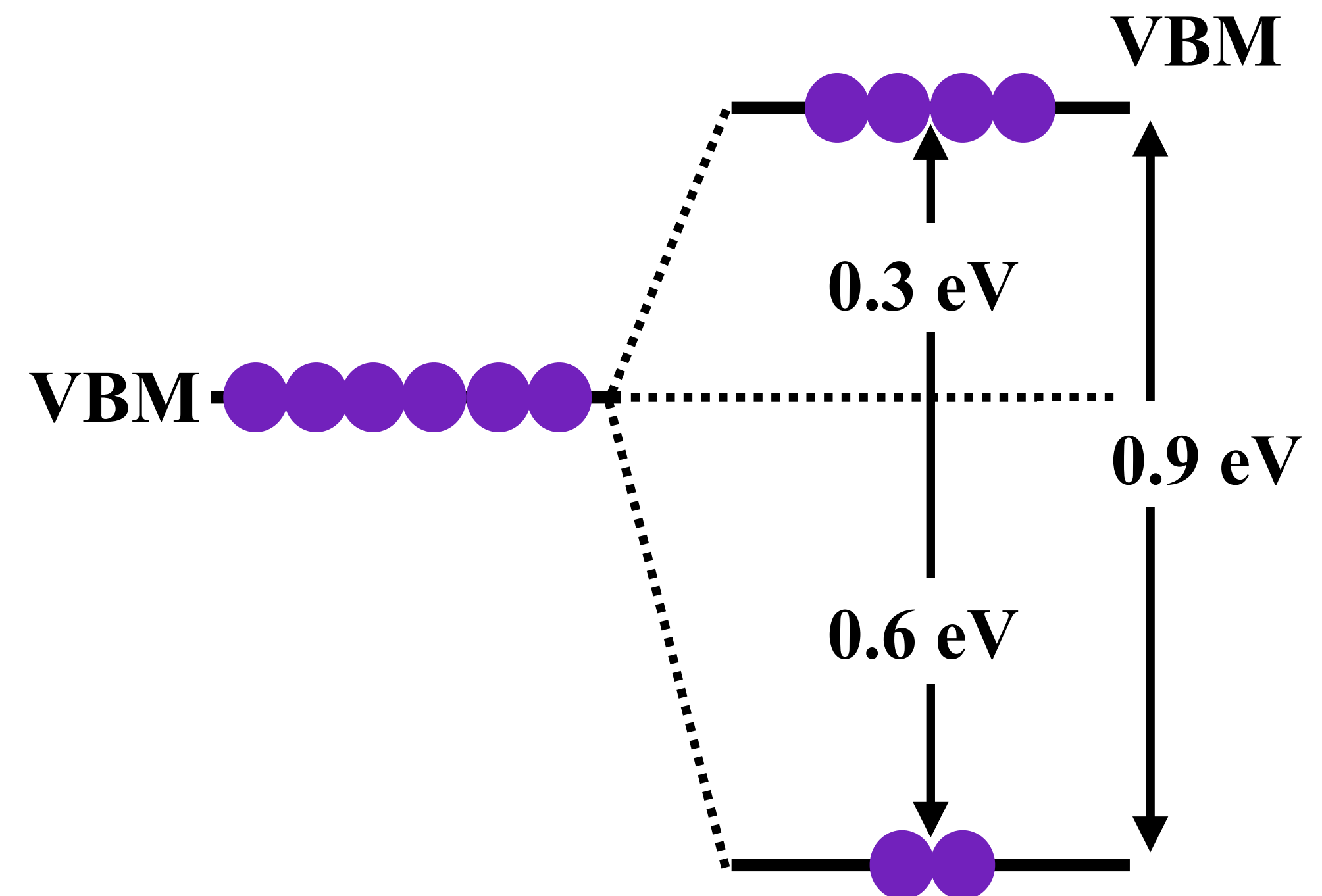
**Correct band gap, effective masses,
and ionization potential**

Effect of spin-orbit coupling

Hybrid DFT + SOC
(Hartree Fock mixing of 33%)



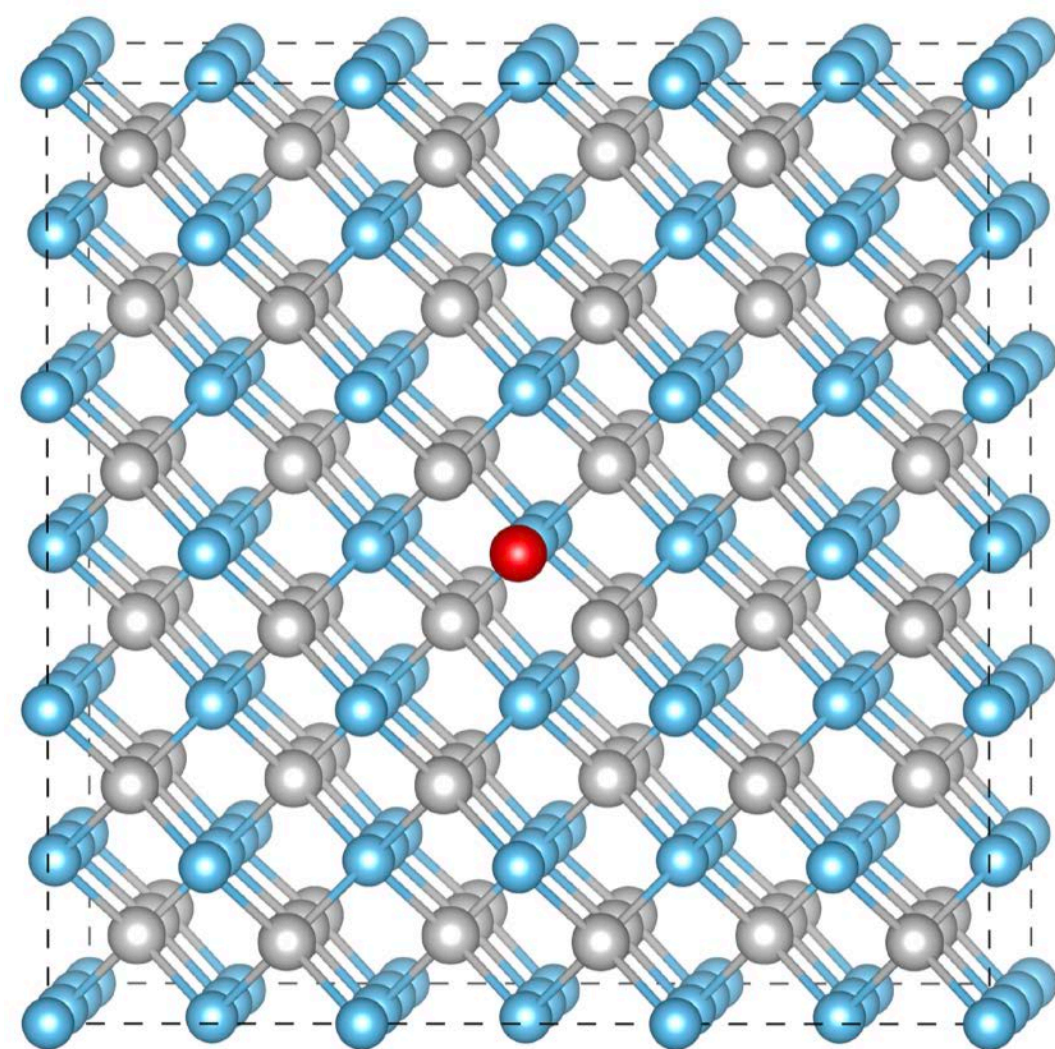
Effect of SOC



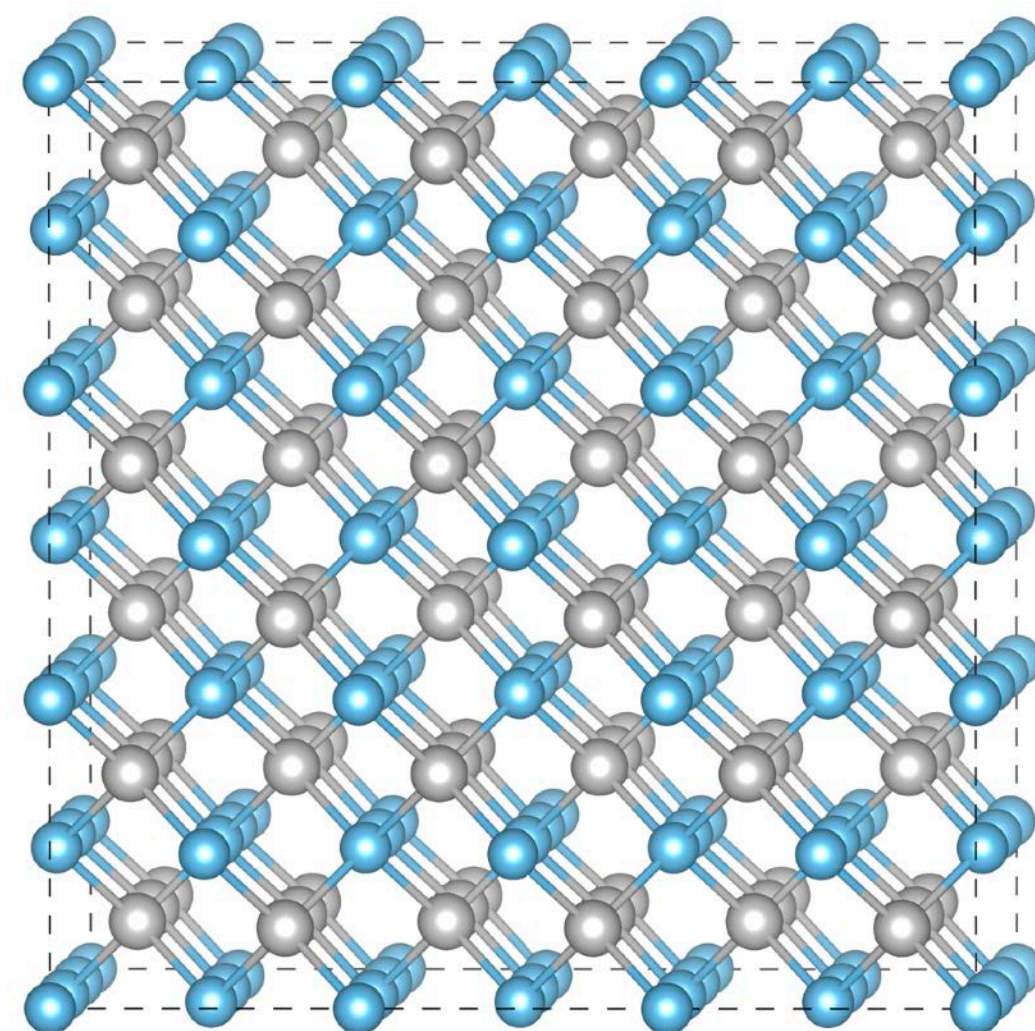
I. Chatratin, B. Dou, S.H. Wei and A. Janotti, J. Phys. Chem. Lett. **14**, 273 (2023)
J. Pan *et al.*, Phy. Rev. B **98**, 054108 (2018)

Formation energies of defects

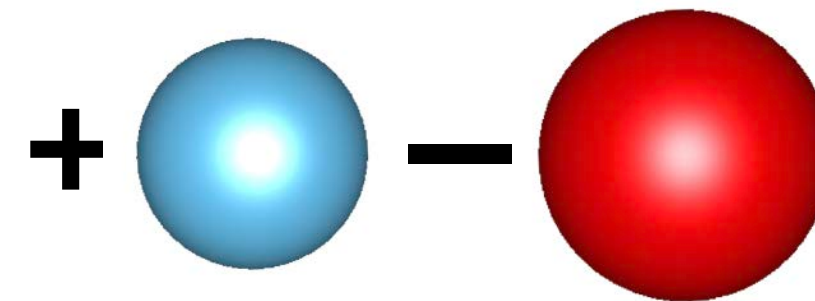
$$E^f[X^q] = E_{tot}[X^q] - E_{tot}[bulk] + \sum_i n_i \mu_i + q(\varepsilon_f + E_{VBM}) + \Delta^q$$



supercell with
a defect in charge q



216-atom perfect
supercell



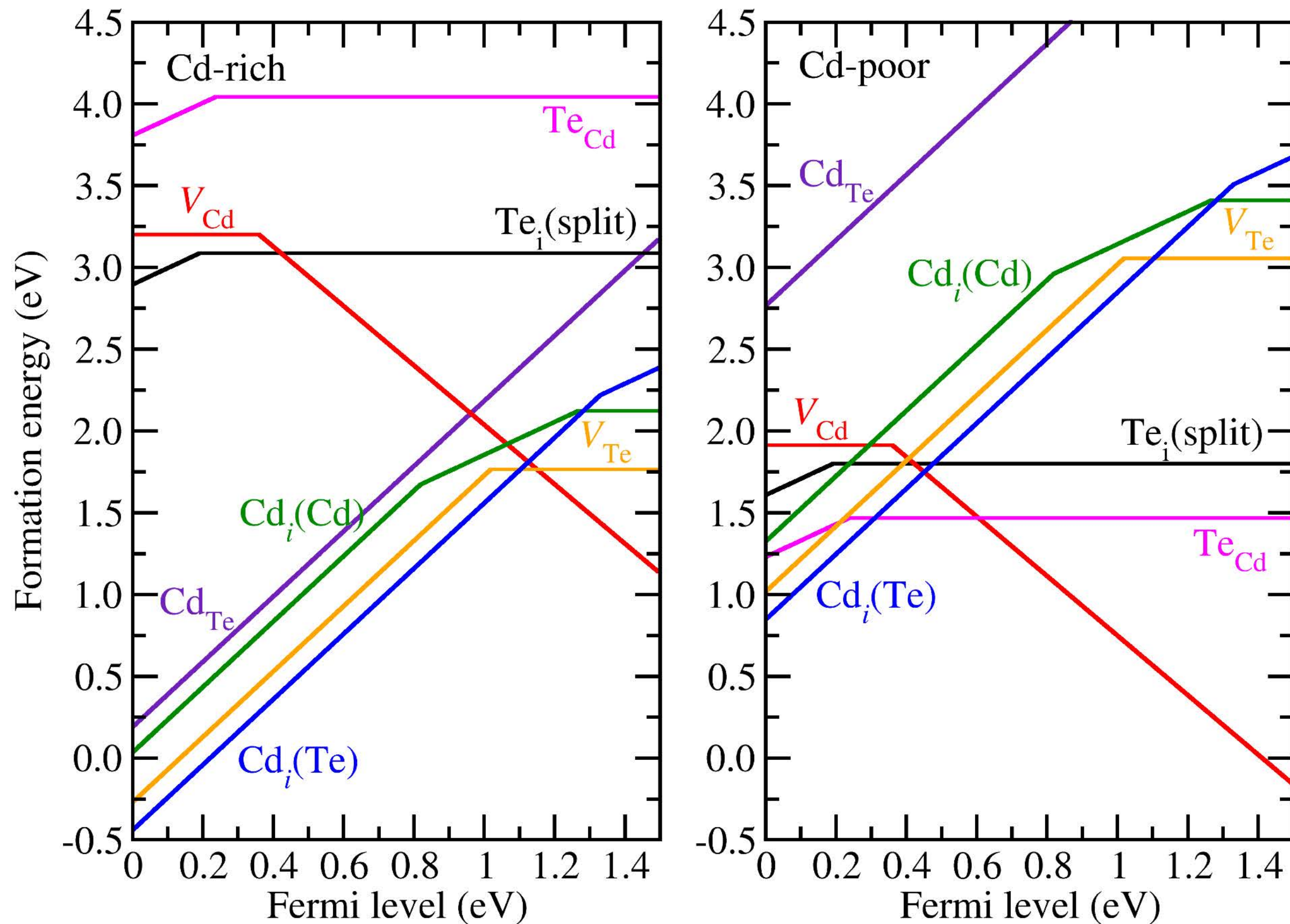
Chemical potential
Cd-rich \rightarrow Cd-poor

Conduction band

..... ε_f Fermi level

Valence band

Formation energies of native defects in CdTe



Similar to previous calculations, but not quite

J.-H. Yang *et al.*, Semicond Sci Technol **31**, 083002 (2016)

J. Pan *et al.*, Phys Rev B **98**, 054108 (2018)

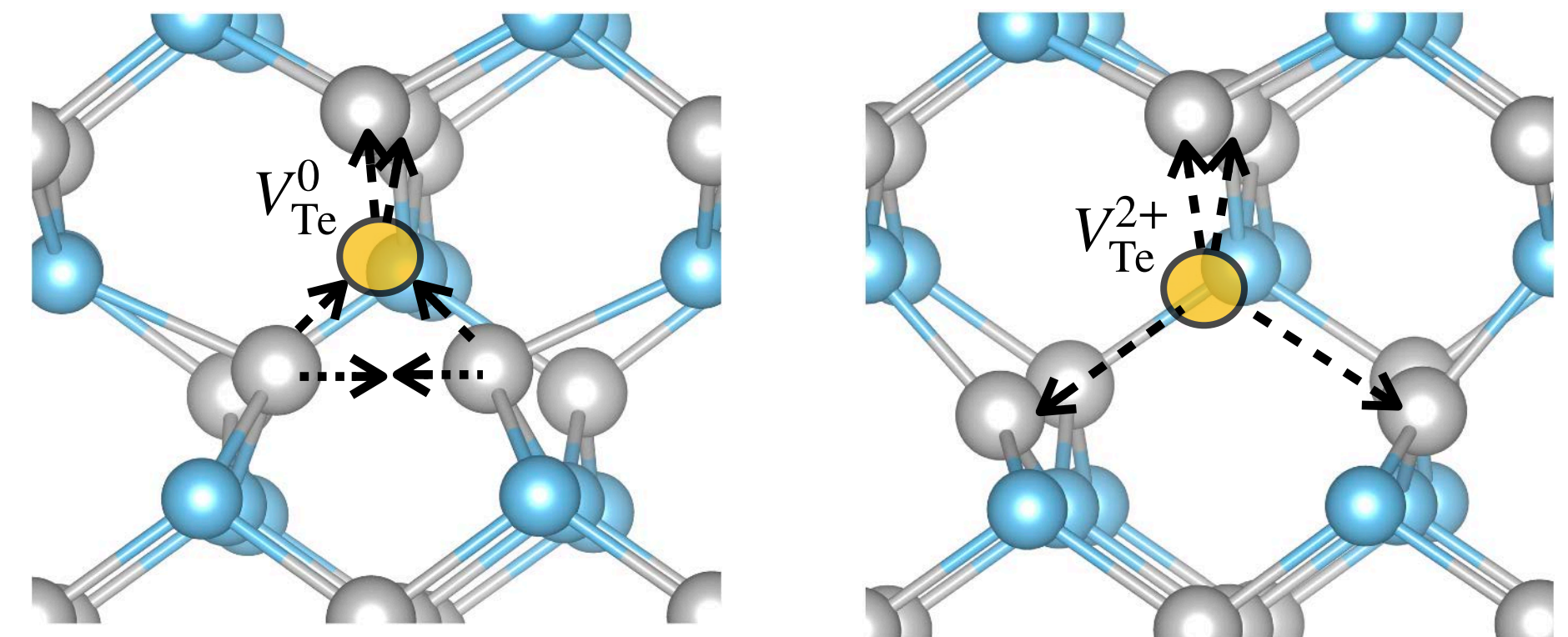
S. R. Kavanagh *et al.*, ACS Energy Lett **6**, 1392 (2021)

Cd-rich conditions

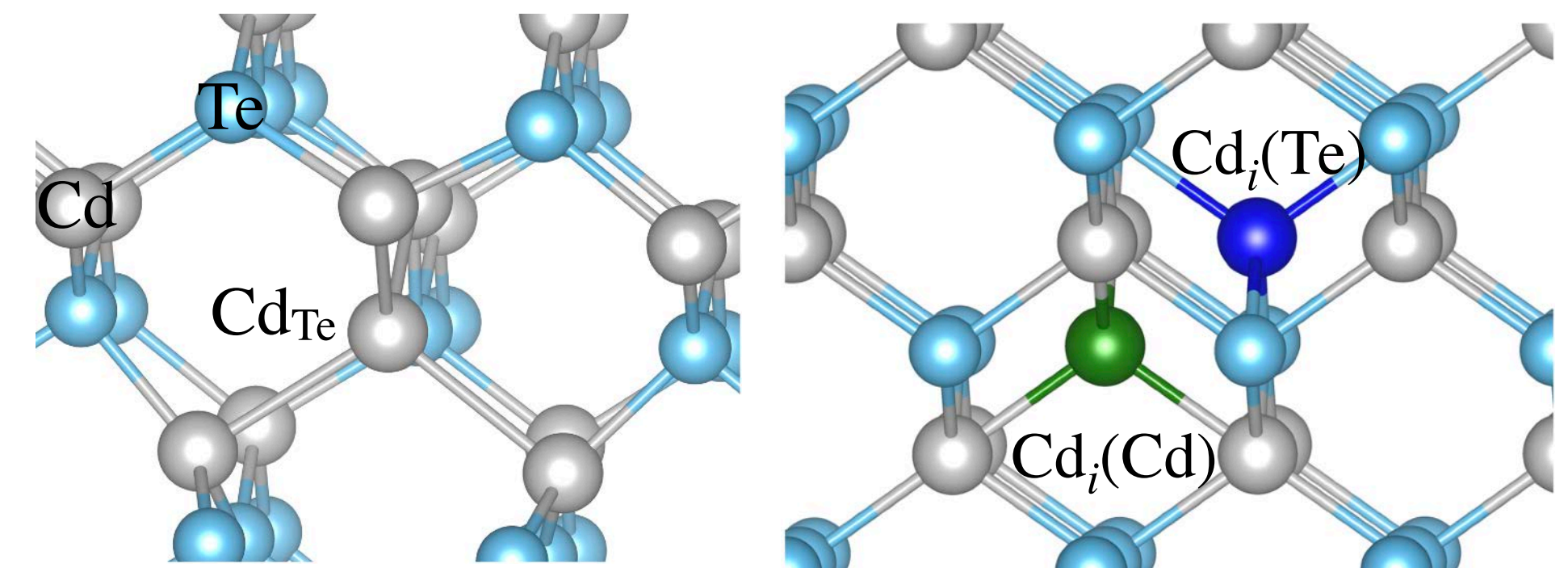
○ Lowest energy defects are donors

⇒ Cd_i V_{Te} Cd_{Te}

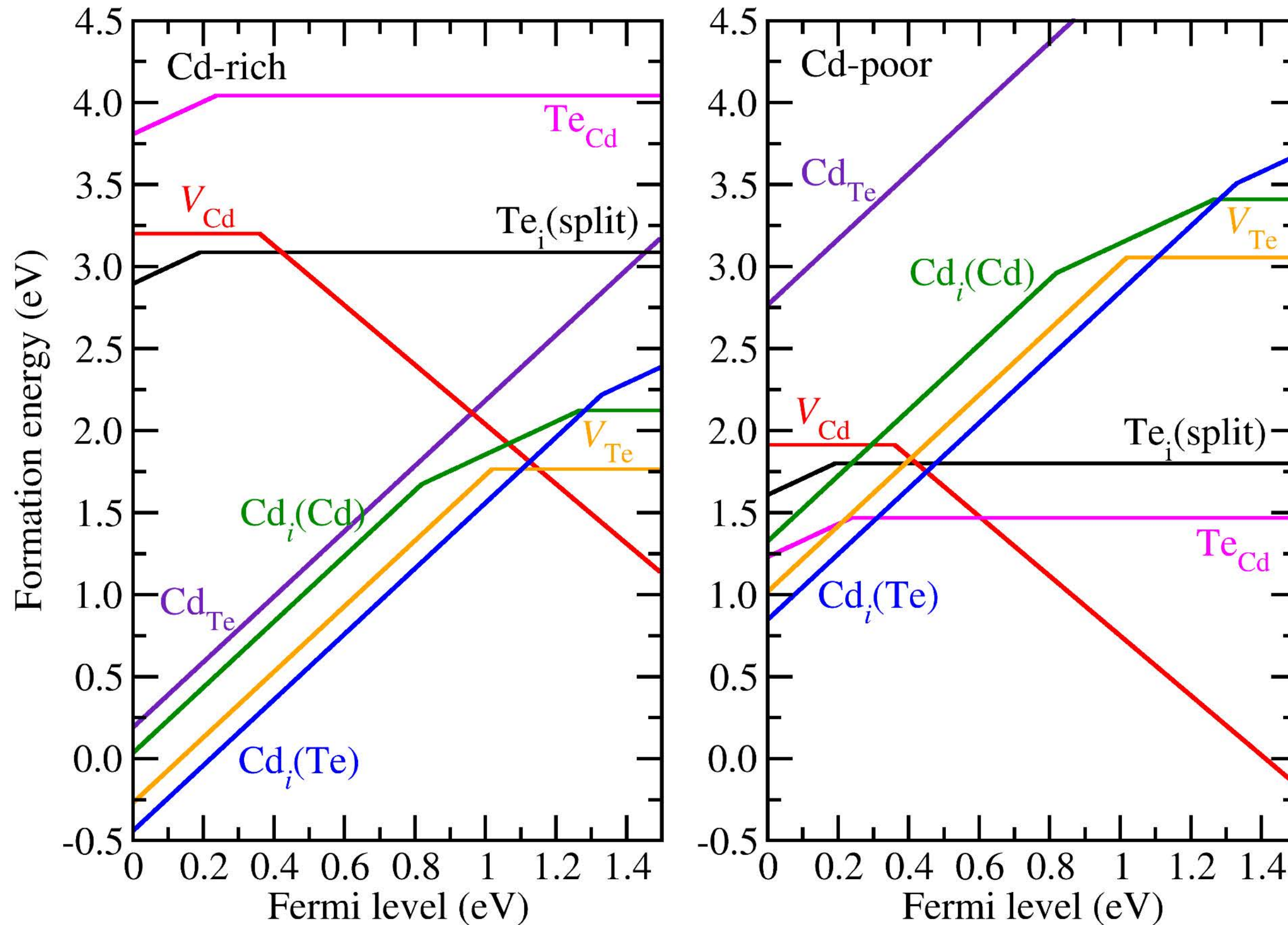
○ V_{Te} is deep donor with $(2+/0)$ at 1.0 eV



○ Cd_i and Cd_{Te} are shallow donors

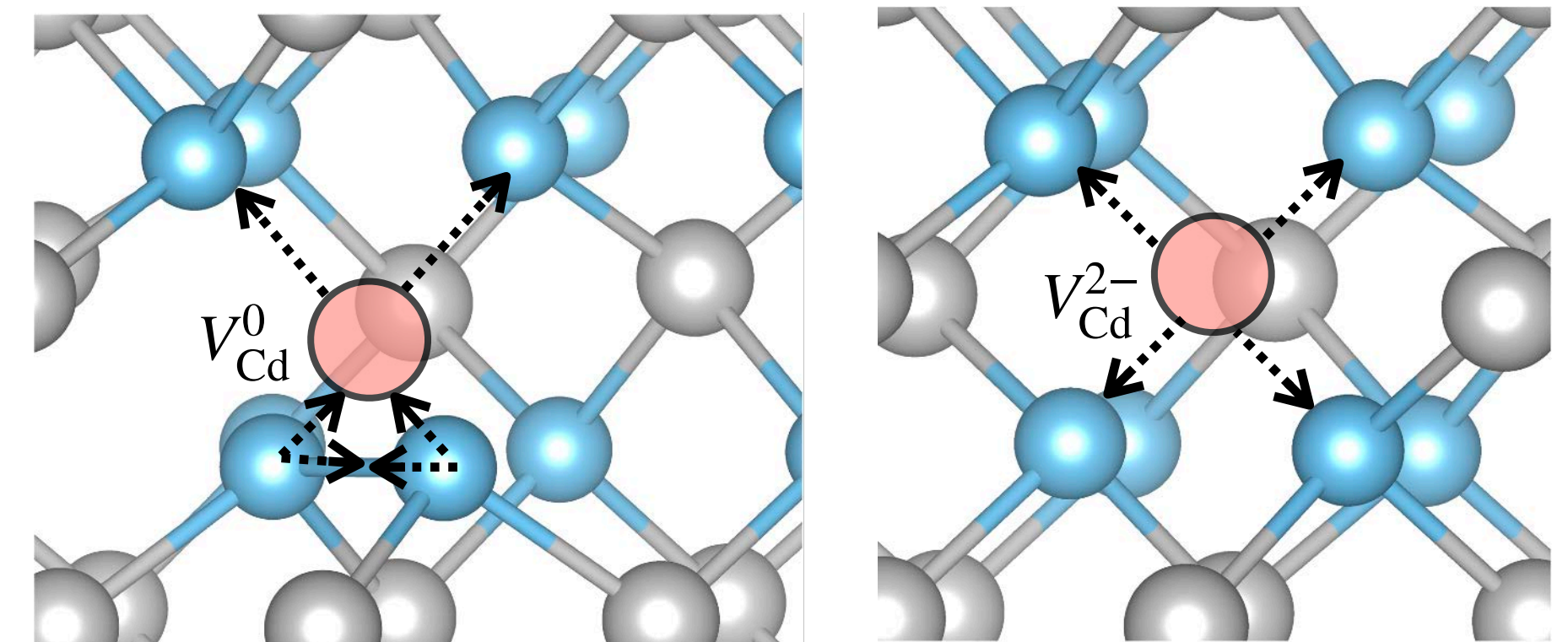


Formation energies of native defects in CdTe



Cd-poor conditions

- Cd_i , V_{Te} and Te_{Cd} are the lowest energy defects in p-type CdTe
- V_{Cd} is the dominant acceptor in n-type CdTe
- V_{Cd} is deep acceptor with (0/2-) at 0.36 eV \Rightarrow cannot lead to p-type conductivity

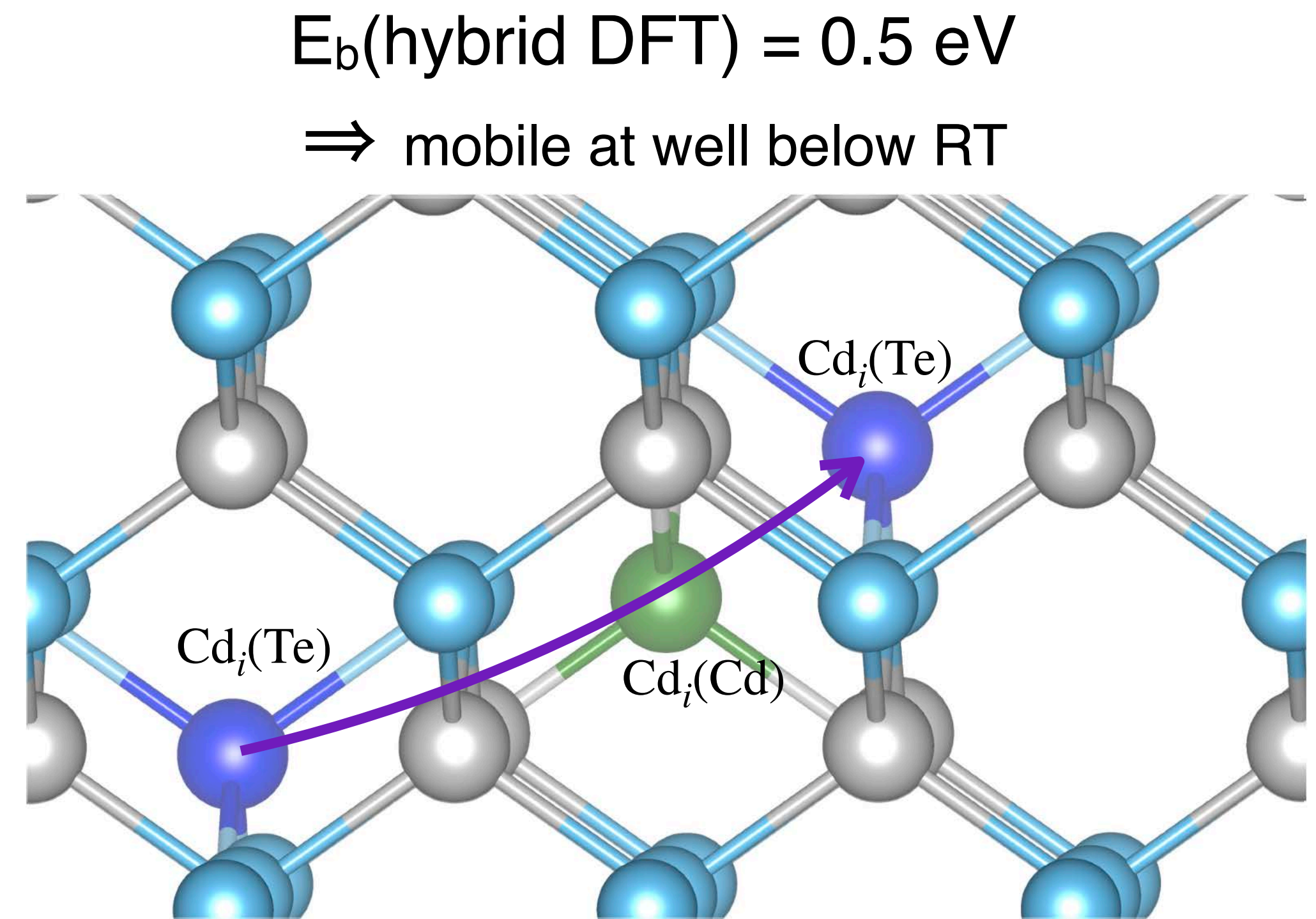
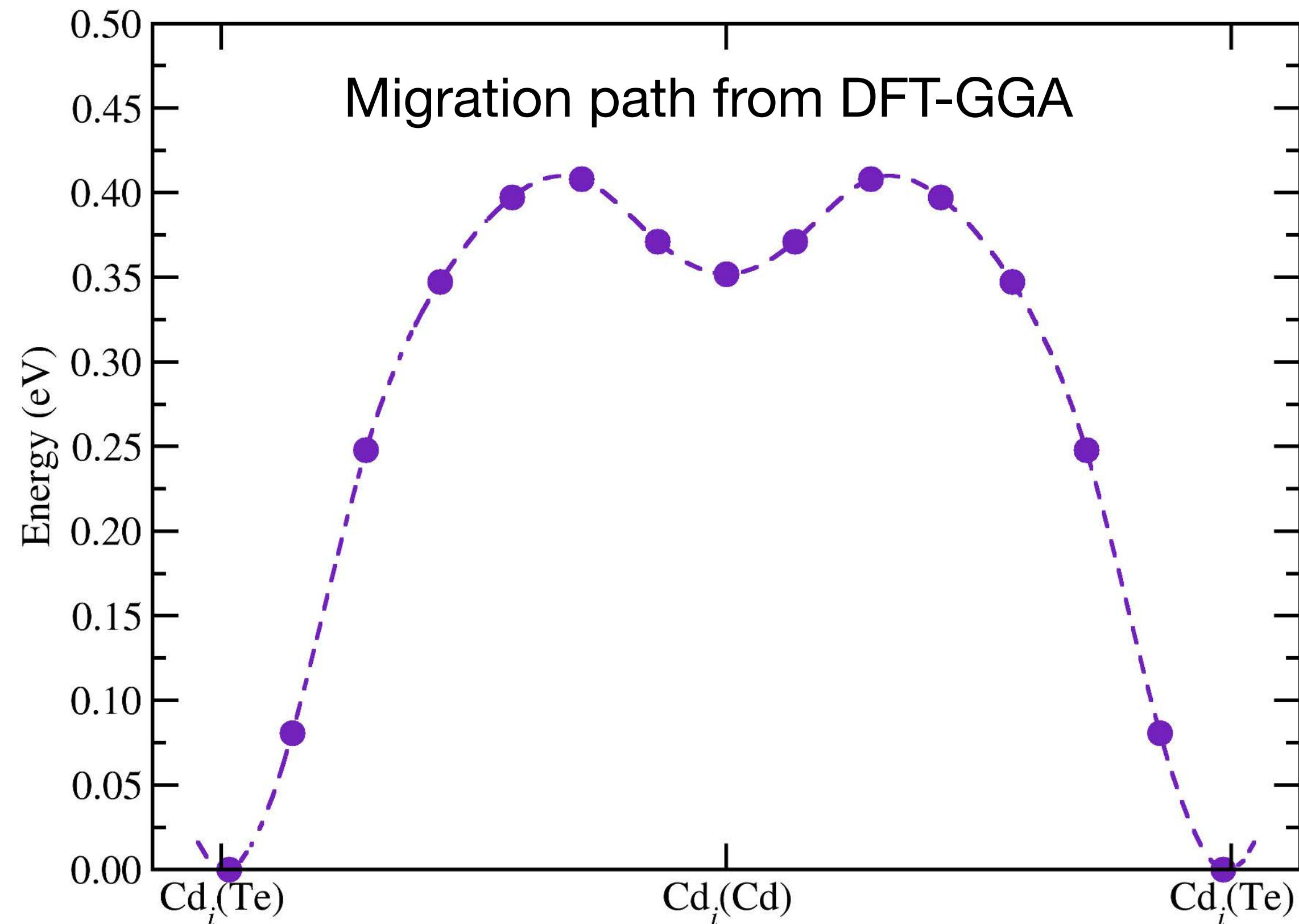


- **Without external dopants, CdTe cannot be p-type**
- **Increasing hole concentration must rely on Group-V (As, P, and Sb) doping**

Cd interstitial stability

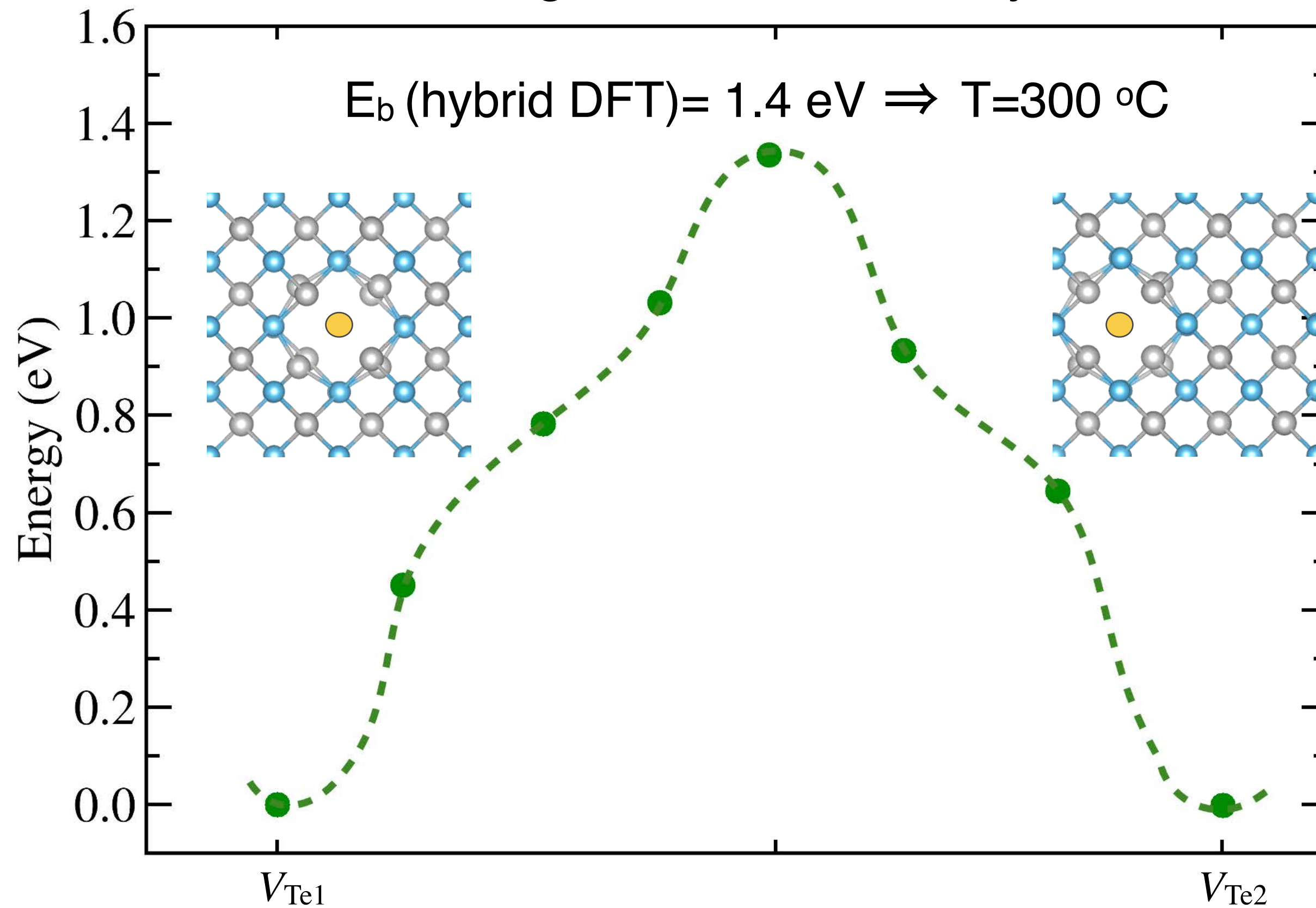
$$\Gamma = \Gamma_o e^{-E_b/k_B T}, \text{ assuming } \Gamma_o = 5 \text{ THz}$$

- Cd_i has a very low migration barrier
⇒ unstable
⇒ not likely a compensation center, will move out or form complexes

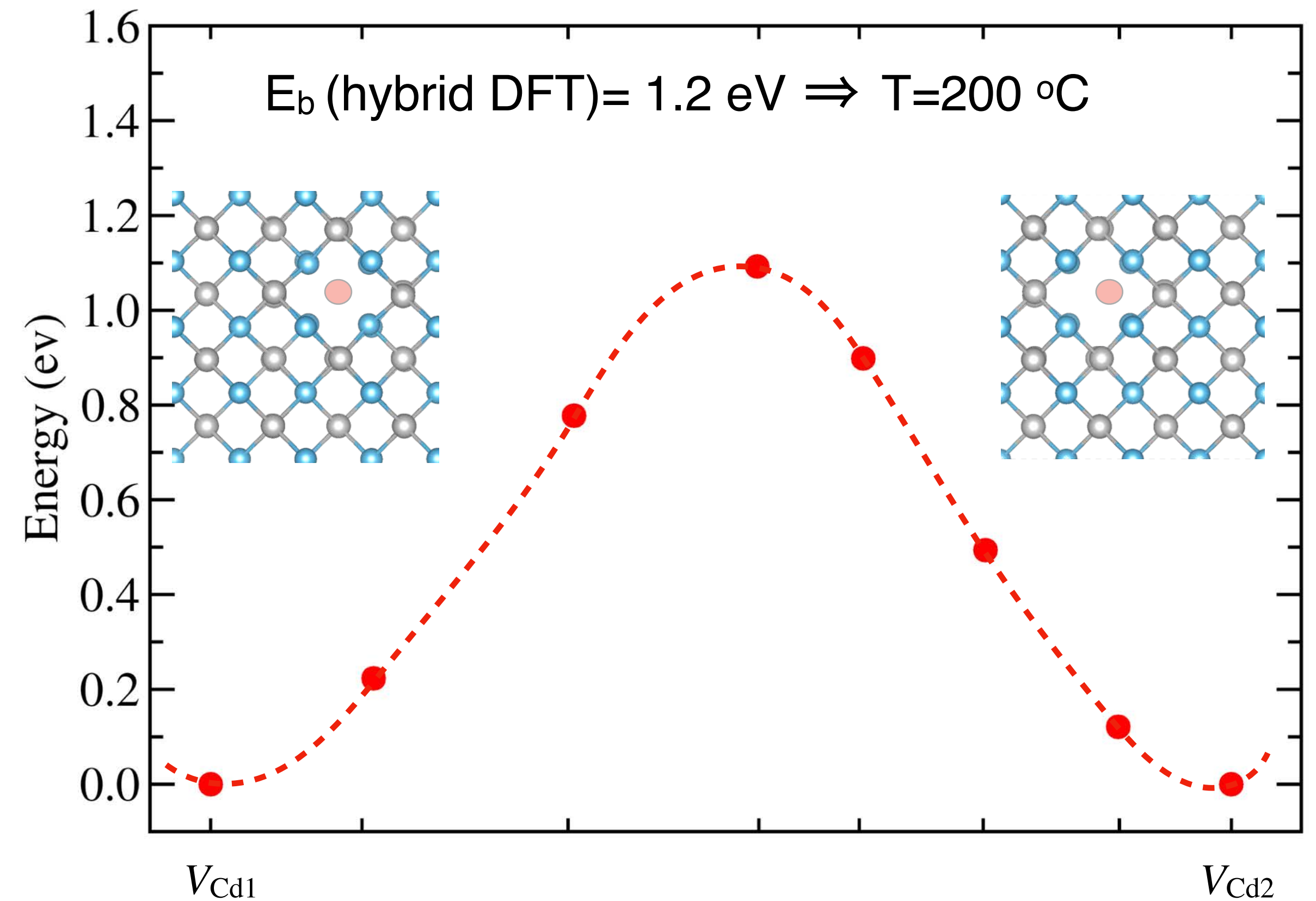


Te and Cd vacancies

Migration of Te vacancy



Migration of Cd vacancy



- The vacancies are stable at the room temperature
- V_{Te} limits hole concentration, acting as a stable compensation center
- V_{Cd} is more mobile than V_{Te}
- V_{Te} may survive post-treatment of p-type CdTe layer (CdCl₂ treatment and annealing at 400-500°C)

Summary

- To explain the electronic properties of CdTe, the inclusion of SOC and the additional Hartree Fock mixing of 33% is required
- For p-type CdTe growth under Cd-rich conditions, Te vacancy is a limiting defect, decreasing hole concentration
- Cd_i is not stable at room temperature and is not a compensation center in *p*-type CdTe
- Cd vacancies is a deep acceptor; cannot lead to *p*-type conductivity

Thank you

intuonc@udel.edu and janotti@udel.edu